

April 2013

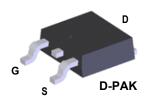
FQD7N10L N-Channel QFET® MOSFET **100 V, 5.8 A, 350 m**Ω

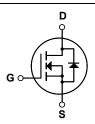
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 5.8 A, 100 V, $R_{DS(on)}$ = 350 m Ω (Max.) @ V_{GS} = 10 V, ID = 2.9 A
- Low Gate Charge (Typ. 4.6 nC)
- · Low Crss (Typ. 12 pF)
- · 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD7N10L	Unit
V _{DSS}	Drain-Source Voltage		100	V
I _D	Drain Current - Continuous (T _C = 25°C)		5.8	Α
	- Continuous (T _C = 100°C)		3.67	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	23.2	Α
V_{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	50	mJ
I _{AR}	Avalanche Current	(Note 1)	5.8	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		25	W
	- Derate above 25°C		0.2	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQD7N10L	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	5.0	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *	50	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	110	°C/W	

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA				V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V			1	μА
		V _{DS} = 80 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		2.0	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 2.9 A		0.275	0.35	5
D3(011)	On-Resistance	V _{GS} = 5 V, I _D = 2.9 A		0.300	0.38	Ω
g _{FS}	Forward Transconductance	V _{DS} = 30 V, I _D = 2.9 A		4.6		S
Dvnam	ic Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		220	290	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		55	72	pF
C _{rss}	Reverse Transfer Capacitance			12	15	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 50 V, I _D = 7.3 A,		9	30	ns
t _r	Turn-On Rise Time	$V_{DD} = 50 \text{ V}, I_D = 7.3 \text{ A},$ $R_G = 25 \Omega$		100	210	ns
t _{d(off)}	Turn-Off Delay Time	116 - 20 32		17	45	ns
t _f	Turn-Off Fall Time	(Note 4)		50	110	ns
Qg	Total Gate Charge	V _{DS} = 80 V, I _D = 7.3 A,		4.6	6.0	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 5 V		1.0		nC
Q _{gd}	Gate-Drain Charge	(Note 4)		2.6		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Dic				5.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				23.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 5.8 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 7.3 A,		70		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs		140		nC

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.23mH, I $_{AS}$ = 5.8A, V $_{DD}$ = 25V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C 3. I $_{SD}$ \leq 7.3A, di/dt \leq 300A/ μ s, V $_{DD}$ \leq BV $_{DSS}$, Starting T $_{J}$ = 25°C 4. Essentially independent of operating temperature

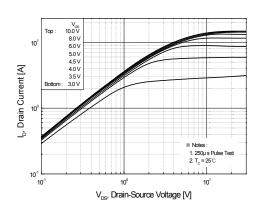


Figure 1. On-Region Characteristics

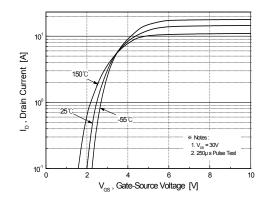


Figure 2. Transfer Characteristics

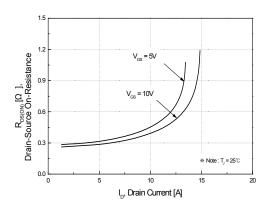


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

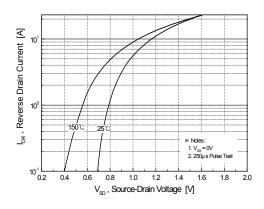


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

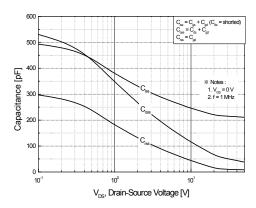


Figure 5. Capacitance Characteristics

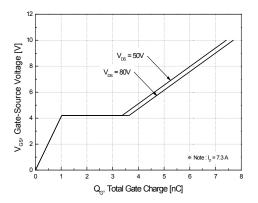


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

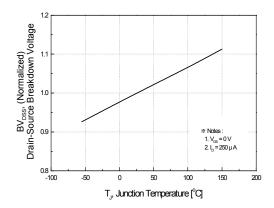
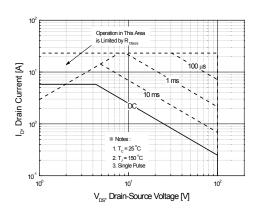


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



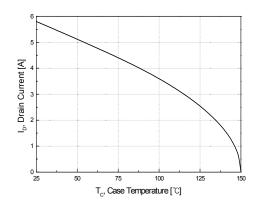


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

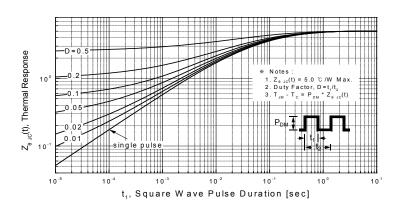
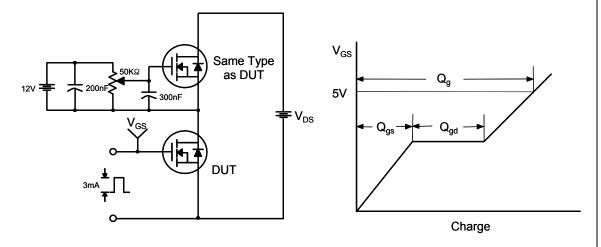
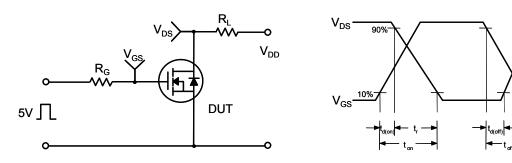


Figure 11. Transient Thermal Response Curve

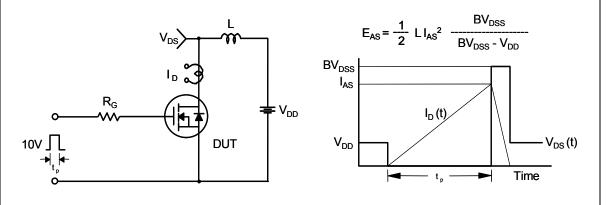
Gate Charge Test Circuit & Waveform



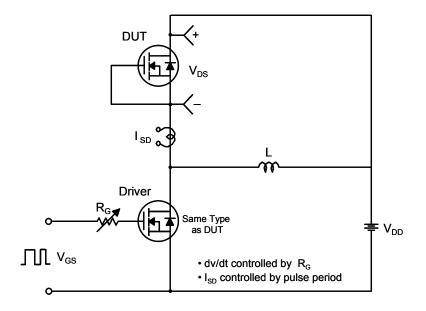
Resistive Switching Test Circuit & Waveforms

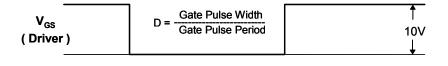


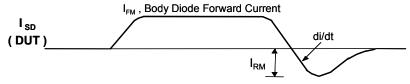
Unclamped Inductive Switching Test Circuit & Waveforms



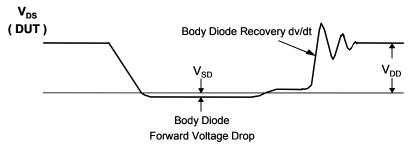
Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Reverse Current



Package Dimensions DPAK Α - 6.00 MIN → 1.27 6.50 MIN 6.22 5.97 _1.02 MAX 6.25 C Ħ 2 MIN 3.00 (0.59)0.89 0.64 1.40 MIN 2.30 2.29 ⊕ 0.25 A A C 4.60 4.57 LAND PATTERN RECOMMENDATION 4.32 MIN NOTE D 5.21 MIN SEE 10.41 9.40 DETAIL A △ 0.10 B 0.51 NOTES: UNLESS OTHERWISE SPECIFIED A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA. B) ALL DIMENSIONS ARE IN MILLIMETERS. C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994. D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION. E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL. GAGE PLANE 0.61 0.46 (1.54)10 1.78 1.40 0.127 MAX IS OPTIONAL. DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS. LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD T0220P1003X238—3N. DRAWING NUMBER AND REVISION: MKT—T0252A03REV8 SEATING PLANE **- (2.90)** DETAIL A (ROTATED -90°) SCALE: 12X





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